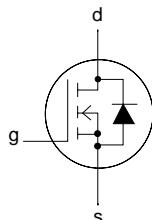


**PowerMOS transistors  
Avalanche energy rated**
**PHB11N50E, PHW11N50E****FEATURES**

- Repetitive Avalanche Rated
- Fast switching
- Stable off-state characteristics
- High thermal cycling performance
- Low thermal resistance

**SYMBOL****QUICK REFERENCE DATA**

$$V_{DSS} = 500 \text{ V}$$

$$I_D = 10.9 \text{ A}$$

$$R_{DS(ON)} \leq 0.55 \Omega$$

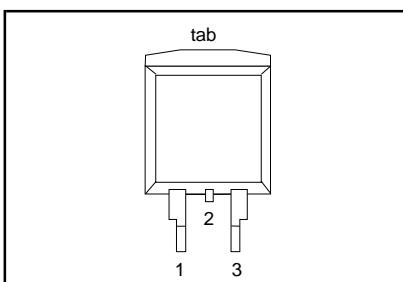
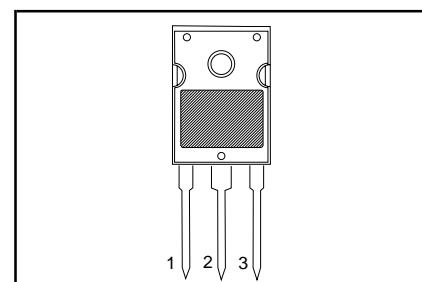
**GENERAL DESCRIPTION**

N-channel, enhancement mode field-effect power transistor, intended for use in off-line switched mode power supplies, T.V. and computer monitor power supplies, d.c. to d.c. converters, motor control circuits and general purpose switching applications.

The PHW11N50E is supplied in the SOT429 (TO247) conventional leaded package.  
The PHB11N50E is supplied in the SOT404 surface mounting package.

**PINNING**

PIN	DESCRIPTION
1	gate
2	drain <sup>1</sup>
3	source
tab	drain

**SOT404****SOT429 (TO247)****LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DSS}$	Drain-source voltage	$T_j = 25 \text{ }^\circ\text{C to } 150 \text{ }^\circ\text{C}$	-	500	V
$V_{DGR}$	Drain-gate voltage	$T_j = 25 \text{ }^\circ\text{C to } 150 \text{ }^\circ\text{C}; R_{GS} = 20 \text{ k}\Omega$	-	500	V
$V_{GS}$	Gate-source voltage		-	$\pm 30$	V
$I_D$	Continuous drain current	$T_{mb} = 25 \text{ }^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	10.9	A
$I_{DM}$		$T_{mb} = 100 \text{ }^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	6.9	A
$P_D$	Pulsed drain current	$T_{mb} = 25 \text{ }^\circ\text{C}$	-	44	A
$T_j, T_{stg}$	Total dissipation	$T_{mb} = 25 \text{ }^\circ\text{C}$	-	156	W
	Operating junction and storage temperature range		-55	150	$^\circ\text{C}$

<sup>1</sup> It is not possible to make connection to pin 2 of the SOT404 package.

**PowerMOS transistors  
Avalanche energy rated**
**PHB11N50E, PHW11N50E**
**AVALANCHE ENERGY LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

<b>SYMBOL</b>	<b>PARAMETER</b>	<b>CONDITIONS</b>	<b>MIN.</b>	<b>MAX.</b>	<b>UNIT</b>
E <sub>AS</sub>	Non-repetitive avalanche energy	Unclamped inductive load, I <sub>AS</sub> = 10.9 A; t <sub>p</sub> = 0.2 ms; T <sub>j</sub> prior to avalanche = 25°C; V <sub>DD</sub> ≤ 50 V; R <sub>GS</sub> = 50 Ω; V <sub>GS</sub> = 10 V	-	707	mJ
E <sub>AR</sub>	Repetitive avalanche energy <sup>2</sup>	I <sub>AR</sub> = 10.9 A; t <sub>p</sub> = 2.5 μs; T <sub>j</sub> prior to avalanche = 25°C; R <sub>GS</sub> = 50 Ω; V <sub>GS</sub> = 10 V	-	18	mJ
I <sub>AS</sub> , I <sub>AR</sub>	Repetitive and non-repetitive avalanche current		-	10.9	A

**THERMAL RESISTANCES**

<b>SYMBOL</b>	<b>PARAMETER</b>	<b>CONDITIONS</b>	<b>MIN.</b>	<b>TYP.</b>	<b>MAX.</b>	<b>UNIT</b>
R <sub>th j-mb</sub>	Thermal resistance junction to mounting base		-	-	0.8	K/W
R <sub>th j-a</sub>	Thermal resistance junction to ambient	SOT78 package, in free air SOT429 package, in free air SOT404 package, pcb mounted, minimum footprint	- - -	60 45 50	- - -	K/W K/W K/W

**ELECTRICAL CHARACTERISTICS**
T<sub>j</sub> = 25 °C unless otherwise specified

<b>SYMBOL</b>	<b>PARAMETER</b>	<b>CONDITIONS</b>	<b>MIN.</b>	<b>TYP.</b>	<b>MAX.</b>	<b>UNIT</b>
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> = 0 V; I <sub>D</sub> = 0.25 mA	500	-	-	V
ΔV <sub>(BR)DSS</sub> / ΔT <sub>j</sub>	Drain-source breakdown voltage temperature coefficient	V <sub>DS</sub> = V <sub>GS</sub> ; I <sub>D</sub> = 0.25 mA	-	0.1	-	%/K
R <sub>DS(ON)</sub>	Drain-source on resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 5.5 A	-	0.47	0.55	Ω
V <sub>GS(TO)</sub>	Gate threshold voltage	V <sub>DS</sub> = V <sub>GS</sub> ; I <sub>D</sub> = 0.25 mA	2.0	3.0	4.0	V
g <sub>fs</sub>	Forward transconductance	V <sub>DS</sub> = 30 V; I <sub>D</sub> = 5.5 A	4	6.5	-	S
I <sub>DSS</sub>	Drain-source leakage current	V <sub>DS</sub> = 500 V; V <sub>GS</sub> = 0 V	-	1	25	μA
I <sub>GSS</sub>	Gate-source leakage current	V <sub>DS</sub> = 400 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 125 °C	-	60	500	μA
V <sub>GS</sub> = ±30 V; V <sub>DS</sub> = 0 V		-	10	200	nA	
Q <sub>g(tot)</sub>	Total gate charge	I <sub>D</sub> = 11 A; V <sub>DD</sub> = 400 V; V <sub>GS</sub> = 10 V	-	75	100	nC
Q <sub>gs</sub>	Gate-source charge	-	7	12	-	nC
Q <sub>gd</sub>	Gate-drain (Miller) charge	-	39	55	-	nC
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 250 V; R <sub>D</sub> = 22 Ω;	-	11	-	ns
t <sub>r</sub>	Turn-on rise time	R <sub>G</sub> = 5.6 Ω	-	38	-	ns
t <sub>d(off)</sub>	Turn-off delay time		-	92	-	ns
t <sub>f</sub>	Turn-off fall time		-	40	-	ns
L <sub>d</sub>	Internal drain inductance	Measured from tab to centre of die	-	3.5	-	nH
L <sub>d</sub>	Internal drain inductance	Measured from drain lead to centre of die (SOT429 package only)	-	4.5	-	nH
L <sub>s</sub>	Internal source inductance	Measured from source lead to source bond pad	-	7.5	-	nH
C <sub>iss</sub>	Input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz	-	1326	-	pF
C <sub>oss</sub>	Output capacitance	-	182	-	-	pF
C <sub>rss</sub>	Feedback capacitance	-	96	-	-	pF

2 pulse width and repetition rate limited by T<sub>j</sub> max.

PowerMOS transistors  
Avalanche energy rated

PHB11N50E, PHW11N50E

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

$T_j = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_S$	Continuous source current (body diode)	$T_{mb} = 25^\circ\text{C}$	-	-	10.9	A
$I_{SM}$	Pulsed source current (body diode)	$T_{mb} = 25^\circ\text{C}$	-	-	44	A
$V_{SD}$	Diode forward voltage	$I_S = 11 \text{ A}; V_{GS} = 0 \text{ V}$	-	-	1.2	V
$t_{rr}$ $Q_{rr}$	Reverse recovery time Reverse recovery charge	$I_S = 11 \text{ A}; V_{GS} = 0 \text{ V}; dI/dt = 100 \text{ A}/\mu\text{s}$	-	630 6.9	-	ns $\mu\text{C}$

## PowerMOS transistors Avalanche energy rated

**PHB11N50E, PHW11N50E**

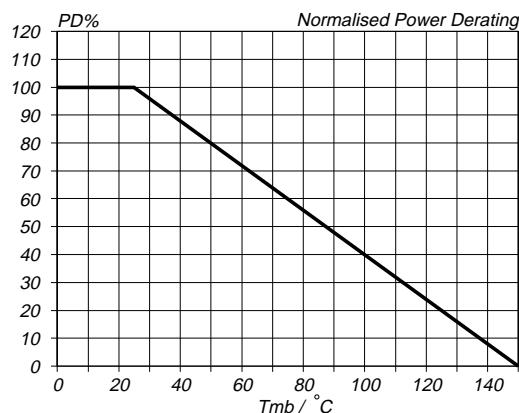


Fig.1. Normalised power dissipation.  
 $PD\% = 100 \cdot P_D/P_{D,25^\circ C} = f(T_{mb})$

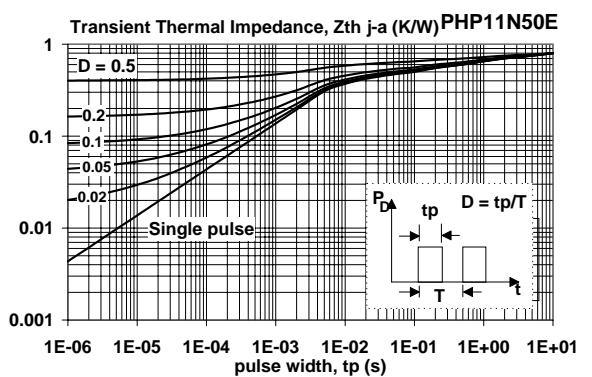


Fig.4. Transient thermal impedance.  
 $Z_{th,j-mb} = f(t); \text{parameter } D = t_p/T$

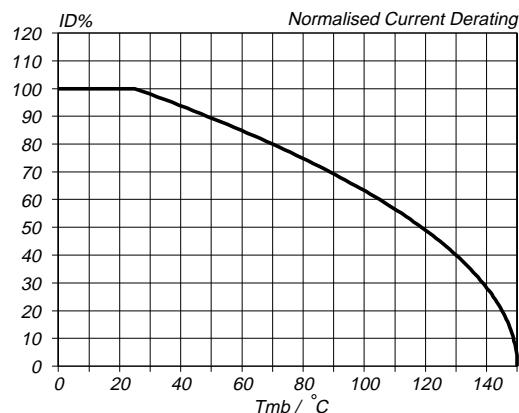


Fig.2. Normalised continuous drain current.  
 $ID\% = 100 \cdot I_D/I_{D,25^\circ C} = f(T_{mb}); \text{conditions: } V_{GS} \geq 10 \text{ V}$

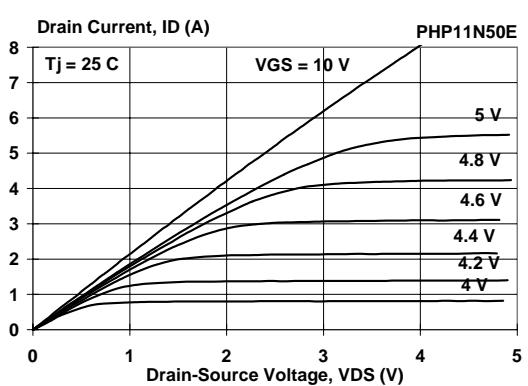


Fig.5. Typical output characteristics.  
 $I_D = f(V_{DS}); \text{parameter } V_{GS}$

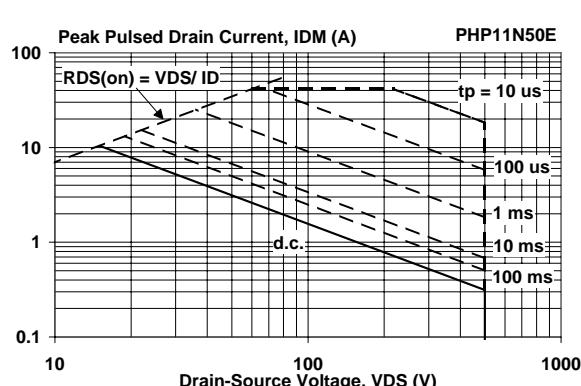


Fig.3. Safe operating area.  $T_{mb} = 25 \text{ }^\circ\text{C}$   
 $I_D \& I_{DM} = f(V_{DS}); I_{DM} \text{ single pulse}; \text{parameter } t_p$

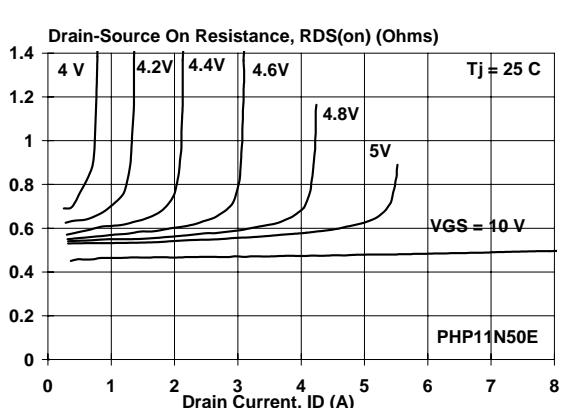


Fig.6. Typical on-state resistance.  
 $R_{DS(ON)} = f(I_D); \text{parameter } V_{GS}$

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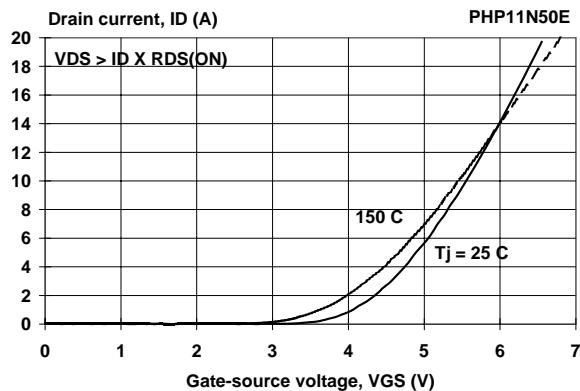


Fig. 7. Typical transfer characteristics.  
 $I_D = f(V_{GS})$ ; parameter  $T_j$

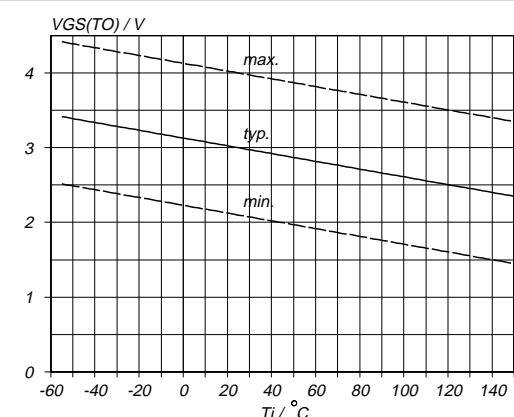


Fig. 10. Gate threshold voltage.  
 $V_{G_{STO}} = f(T_j)$ ; conditions:  $I_D = 0.25$  mA;  $V_{DS} = V_{GS}$

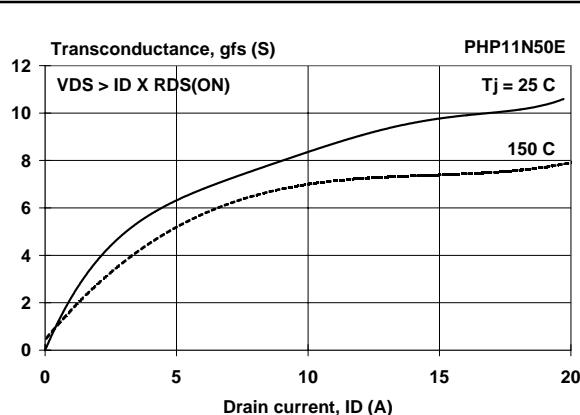


Fig. 8. Typical transconductance.  
 $g_{fs} = f(I_D)$ ; parameter  $T_j$

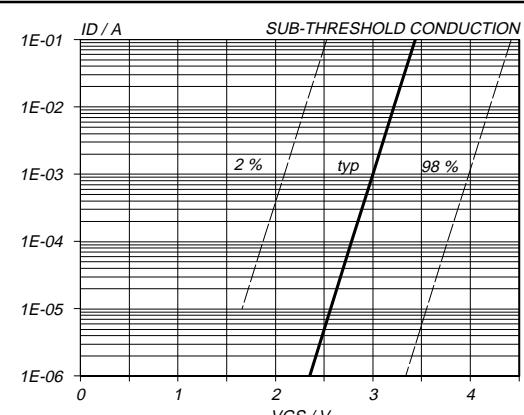


Fig. 11. Sub-threshold drain current.  
 $I_D = f(V_{GS})$ ; conditions:  $T_j = 25$  °C;  $V_{DS} = V_{GS}$

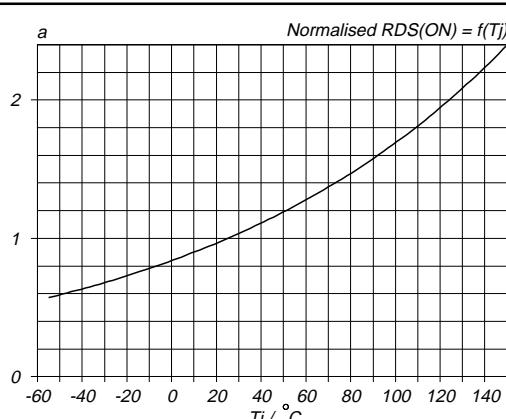


Fig. 9. Normalised drain-source on-state resistance.  
 $a = R_{DS(ON)}/R_{DS(ON)25\text{ }^{\circ}\text{C}} = f(T_j)$ ;  $I_D = 5.5$  A;  $V_{GS} = 10$  V

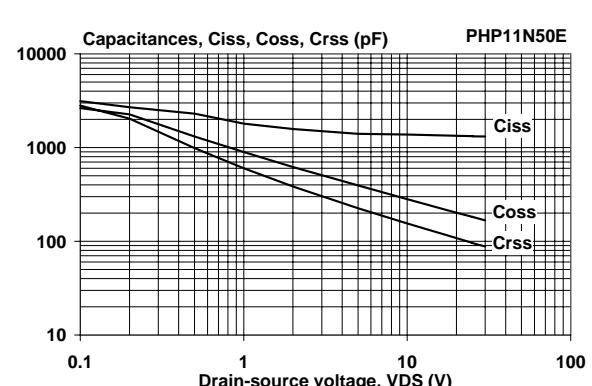


Fig. 12. Typical capacitances,  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$ .  
 $C = f(V_{DS})$ ; conditions:  $V_{GS} = 0$  V;  $f = 1$  MHz

## PowerMOS transistors Avalanche energy rated

**PHB11N50E, PHW11N50E**

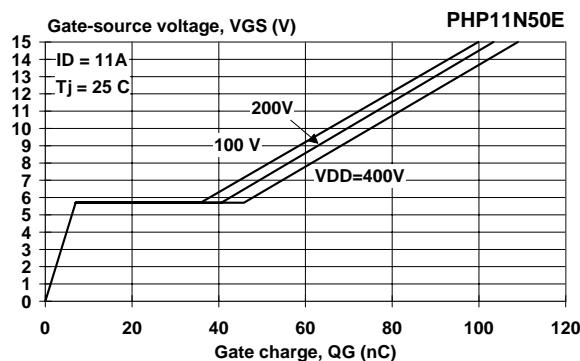


Fig. 13. Typical turn-on gate-charge characteristics.  
 $V_{GS} = f(Q_G)$ ; parameter  $V_{DS}$

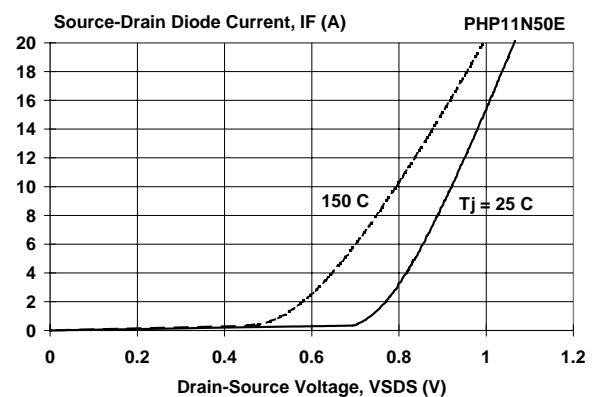


Fig. 16. Source-Drain diode characteristic.  
 $I_F = f(V_{SDS})$ ; parameter  $T_j$

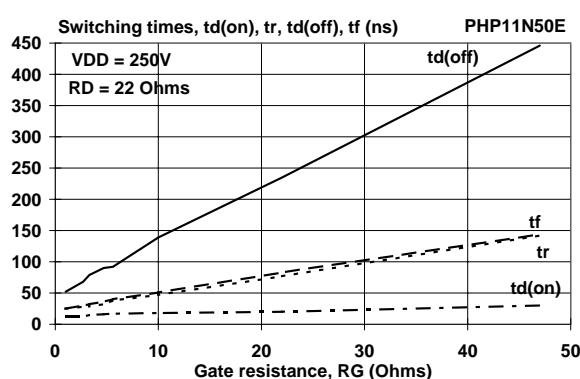


Fig. 14. Typical switching times;  $t_{d(\text{on})}$ ,  $t_r$ ,  $t_{d(\text{off})}$ ,  $t_f = f(R_G)$

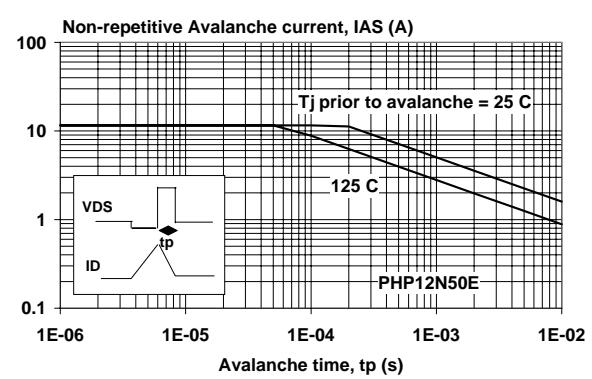


Fig. 17. Maximum permissible non-repetitive avalanche current ( $I_{AS}$ ) versus avalanche time ( $t_p$ ); unclamped inductive load

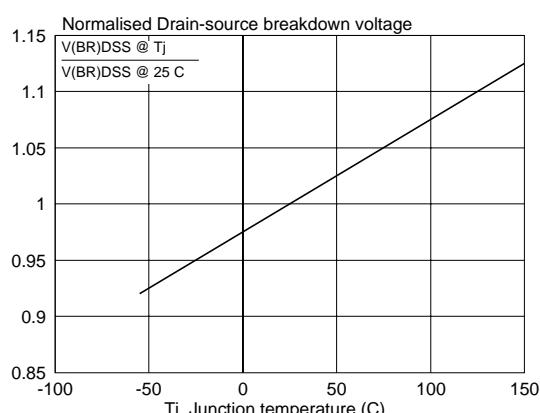


Fig. 15. Normalised drain-source breakdown voltage;  
 $V_{(BR)DSS}/V_{(BR)DSS 25^\circ\text{C}} = f(T_j)$

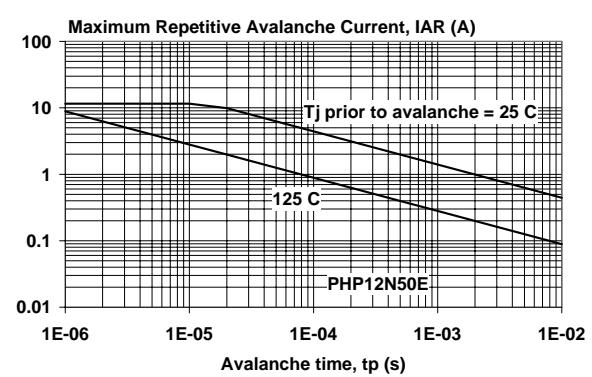


Fig. 18. Maximum permissible repetitive avalanche current ( $I_{AR}$ ) versus avalanche time ( $t_p$ )

**PowerMOS transistors  
Avalanche energy rated**

**PHB11N50E, PHW11N50E**

## MECHANICAL DATA

*Dimensions in mm*

Net Mass: 1.4 g

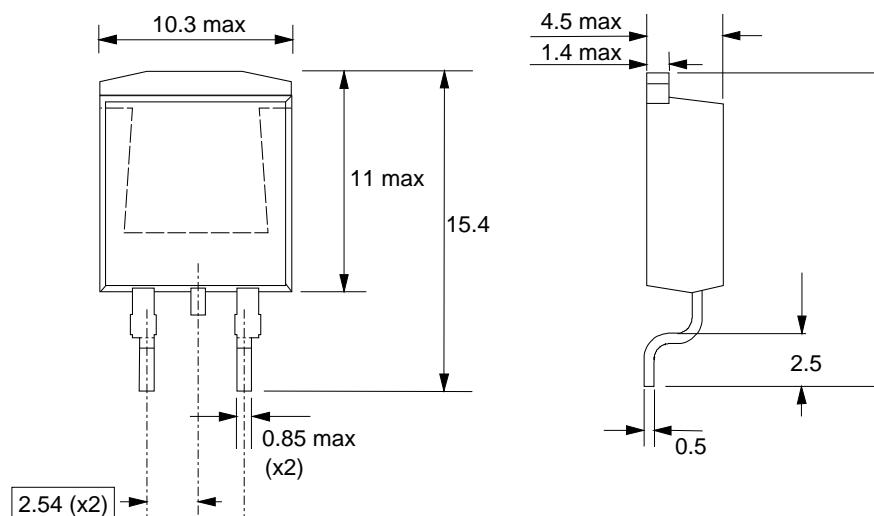


Fig.19. SOT404 : centre pin connected to mounting base.

## MOUNTING INSTRUCTIONS

*Dimensions in mm*

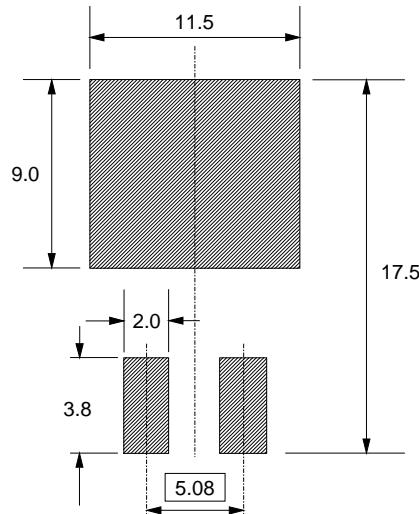


Fig.20. SOT404 : soldering pattern for surface mounting.

### Notes

1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
2. Epoxy meets UL94 V0 at 1/8".

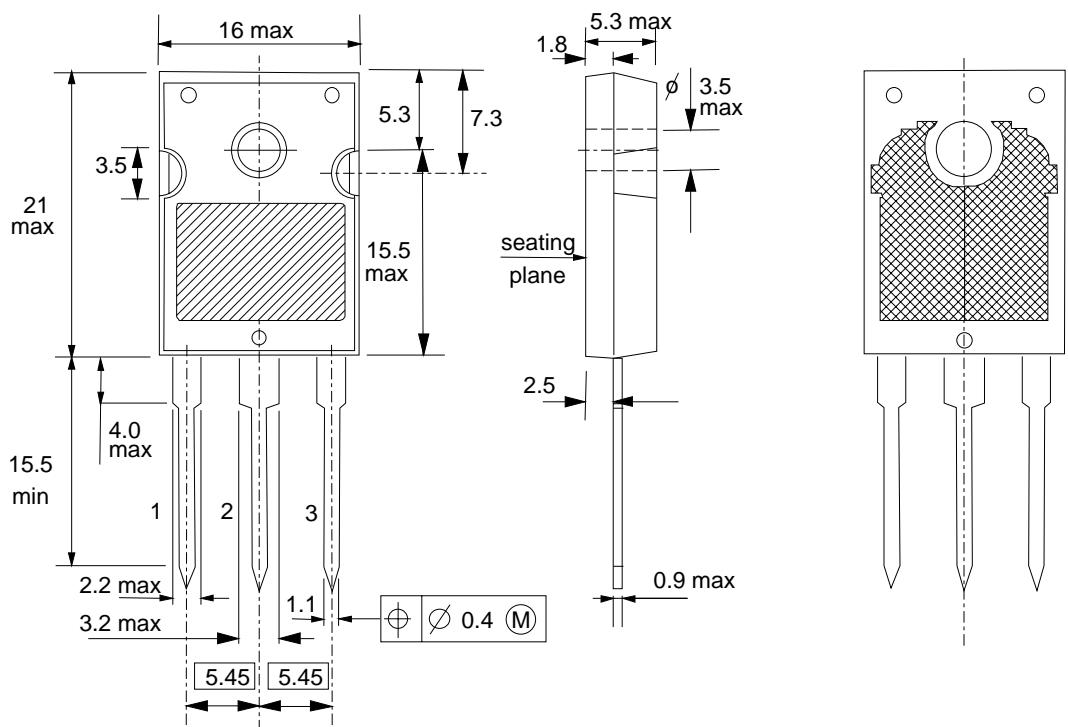
## PowerMOS transistors Avalanche energy rated

## PHB11N50E, PHW11N50E

## **MECHANICAL DATA**

*Dimensions in mm*

*Net Mass: 5 g*



*Fig.21. SOT429; pin 2 connected to mounting base.*

## **Notes**

- Notes**

  1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
  2. Refer to mounting instructions for SOT429 envelope.
  3. Epoxy meets UL94 V0 at 1/8".

PowerMOS transistors  
Avalanche energy rated

PHB11N50E, PHW11N50E

## DEFINITIONS

<b>Data sheet status</b>	
Objective specification	This data sheet contains target or goal specifications for product development.
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.
Product specification	This data sheet contains final product specifications.
<b>Limiting values</b>	
Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.	
<b>Application information</b>	
Where application information is given, it is advisory and does not form part of the specification.	
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